

# Dimple Kochar

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## CONTACT INFORMATION

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## EDUCATION

Massachusetts Institute of Technology

September, 2021 – Present

PhD student, Department of Electrical Engineering & Computer Science  
Advisor: Prof. Anantha Chandrakasan — MIT Energy-Efficient Circuits and Systems  
GPA: 5.0 / 5.0

Indian Institute of Technology Bombay

July, 2016 – August, 2021

Bachelor & Master of Technology, Department of Electrical Engineering  
Specialization: Microelectronics & VLSI  
Minor Degree, Department of Computer Science & Engineering  
GPA: 9.34 / 10.0

Awarded the 'Sharad Maloo Memorial Gold Medal' for being the most outstanding student in terms of extra-curricular activities along with academic performance, among all recipients of B.Tech/DD (B.Tech+M.Tech) degree (1 in 999) at the 59th Convocation of IIT Bombay

## PUBLICATIONS

- **D. Kochar**, T. Samadder, S. Mukhopadhyay and S. Mahapatra, "Modeling of HKMG Stack Process Impact on Gate Leakage, SILC and PBTI," *2021 IEEE International Reliability Physics Symposium (IRPS)*, 2021, pp. 1-7, doi: 10.1109/IRPS46558.2021.9405154. [\[paper\]](#)
- **D. Kochar** and A. Kumar, "Estimation of Time to Failure Distribution in SRAM Due to Trapped Oxide Charges," *2021 IEEE International Symposium on Circuits and Systems (ISCAS)*, 2021, pp. 1-5, doi: 10.1109/ISCAS51556.2021.9401180. [\[paper\]](#)
- T. Samadder, N. Choudhury, S. Kumar, **D. Kochar**, N. Parihar and S. Mahapatra, "A Physical Model for Bulk Gate Insulator Trap Generation During Bias-Temperature Stress in Differently Processed p-Channel FETs," in *IEEE Transactions on Electron Devices*, vol. 68, no. 2, pp. 485-490, Feb. 2021, doi: 10.1109/TED.2020.3045960. [\[paper\]](#)

## RESEARCH PROJECTS

### **Low Power, Low Memory, Secure General Purpose Accelerator for TinyML**

MIT

Advisor: Prof. Anantha Chandrakasan, EECS Department

May '22 - Present

Introduction: The growth in low-power, small area, embedded devices and advancement in the optimization of ML algorithms has resulted in tiny machine learning (TinyML), which calls for implementing the ML algorithm within the IoT device. TinyML is implemented through efficient hardware-software co-design. In this project, the aim is to design an accelerator which is optimized for area (low memory) and power while supporting a multitude of applications like voice activation, ECG, keyword spotting, visual wake word, pupil detection, time series, noise cancellation, etc.

- Designing a fused layer computation flow, with a light cryptographic engine for security
- Targeting total memory of 20kB, with weight storage on chip at near threshold voltage
- Motivated by the idea of an energy harvesting chip, having quantization as a function of energy

### **HKMG Stack Process Impact on Gate Leakage, SILC & PBTI** [\[slides\]](#)

IIT Bombay

Advisor: Prof. Souvik Mahapatra, Electrical Engineering Department

Dec '18 - Oct '20

Introduction: The primary impediment to channel length scaling is gate leakage. PBTI and SILC also get worse at scaled EOT. Recently, RD and RDD models are used for NBTI interface and bulk trap generation in PMOS. This project aims to model direct tunneling leakage, SILC & PBTI along with the traps generated in NMOS with deeply scaled (down to EOT~7Å) HKMG stacks.

- Quantified impact of IL & HK thickness, channel/IL & IL/HK barriers on gate leakage & SILC
- Extracted bulk trap densities from SILC measurements of differently processed NMOS using a WKB tunneling model & used a Reaction-Diffusion-Drift (RDD) framework to model them
- Modelled the traps generated from PBTI stress using the double interface H/H<sub>2</sub> RD framework
- Analysed impact of gate stack process (pre-clean, IL, IL/HK interface, HK & post-HK nitridation) on gate leakage, SILC and PBTI trap generation (using DCIV) at IL/HK interface

**Method for Time To Failure Estimation of SRAM due to RTN** [slides] *IIT Bombay*  
*Advisor: Prof. Animesh Kumar, Electrical Engineering Department* *Dec '18 - Nov '20*

Introduction: Trapping and detrapping of charges in the oxide interface of a MOSFET leads to a random telegraphic noise (RTN) injection & this phenomenon negatively affects the reliability of circuits. The objective of this project is to develop a reproducible strategy to obtain time to failure (TTF) distribution & related statistics for SRAM of any technology with any given RTN model.

- Proposed a method to estimate TTF distribution of a stored bit in an SRAM cell due to single or multi-level RTN by composition of Monte-Carlo simulations & circuit-level abstraction
- Showcased results of this procedure on an SRAM cell made from 45 nm technology with a single-trap RTN model at various supply voltages using Cadence, Ocean and Python scripting
- Indicated via circuit-level simulations that the TTF distribution worsens due to process variations

**Dipole-Exchange Spin Waves in Thin Ferromagnetic Films** [slides] *TU Delft*  
*Advisors: Prof. Gerrit Bauer, Kavli Institute of Nanoscience* *May '19 - Jul '19*  
*Prof. Yaroslav Blanter, Kavli Institute of Nanoscience*

Introduction: Dispersion characteristics of spin waves in ferromagnetic films taking into account both the dipole-dipole and the exchange interactions are obtained by a sixth-order differential equation. The objective of this project is to solve it considering pinned and unpinned boundary conditions & study their variation with thickness in this transition region.

- Calculated the wave function, magnetization & dipolar field profiles for various modes of spin waves by solving Landau–Lifshitz & Maxwells' equations & appropriate boundary conditions
- Showed how chirality changes with thickness; obtained the dispersion relation ( $\omega$  vs  $\vec{k}$ ) for a film
- Obtained isofrequency curves & showed their change with increase in magnetic field in  $\vec{k}$  space

**Model for Time Dependent Dielectric Breakdown for Thin Oxides**[slides] *IIT Bombay*  
*Advisor: Prof. Souvik Mahapatra, Electrical Engineering Department* *May '18 - Jun '21*

Introduction: Time-dependent dielectric breakdown (TDDB) is characterized by its Weibull slope. In this project, the change in the slope is explained by a percolation model with different defect generation rates in the bulk & channel/oxide and gate/oxide interfaces, also considering SILC slope changes with thickness & trap size. The model is then extended for high-k with interfacial SiO<sub>2</sub>.

- Designed a cell based oxide percolation model which stochastically creates bulk & interface traps
- Procured time to failure distribution & analysed the relation of its Weibull slope with oxide thickness & obtained results obeying experimental data varying with voltage & temperature
- Proposed and demonstrated a hypothesis for differences in bulk trap & SILC slopes

#### SCHOLASTIC ACHIEVEMENTS

- Conferred the 'Grass Instrument Company Fellowship' to support first year at MIT
- Bestowed the 'Desai-Sethi Scholarship' awarded to the top 5 girls admitted to IIT Bombay
- Achieved All India Rank 102 in JEE Main and All India Rank 295 in JEE Advanced out of 1.2 & 0.2 million candidates respectively; stood first in both in the state of Maharashtra among girls
- Awarded the 'Travel Grants for UG students by C'1992 and C'1998' for IEEE ISCAS 2021
- Selected for Indian National Chemistry Olympiad (InChO) from among 40K students

#### TECHNICAL PROJECTS

**Ring Oscillator Characterization across Stages and Transistor Size** *Digital Circuits*

- Taped out in 14nm FinFET Samsung technology, ring oscillators of different stages and transistor sizes, each with its own power line for accurate power management and frequency

**Low Power FC-CS CMOS Operational Amplifier** *Analog Circuits*

- Designed an FC-CS CMOS opamp in 22nm bsim4 with power < 1.5mW, settling times < 8ns, open loop gain > 10k, thermal noise < 300uV, phase margin > 65° at gain-of-2 frequency

**Power Amplifier Design for function at 520 MHz** *Solid State Microwave Devices*

- Constructed matching networks using microstrip transmission lines and fabricated it on FR4 substrate to obtain a gain of 2.5 dB at 520 MHz with S<sub>11</sub> and S<sub>12</sub> values -18 dB and -35 dB

### Device Fabrication

- Broadband
- $4 \times 4$
- Butler Matrix Circuit at 5.4GHz
- Microwave Integrated Circuits*

- Music Genre Identification

Machine Learning

- Other projects:

- ## RELEVANT COURSES

**IITB:** Foundation of VLSI CAD; VLSI Design; Algorithmic Design of Digital Systems; Microprocessors; Microwave Integrated Circuits; Solid State Microwave Devices & their Applications; Physics of Transistors; VLSI Technology; Solar Photovoltaic, Fundamentals, Technologies & Applications; Introduction to Condensed Matter Physics

Teaching Assistant for IIT Bombay Courses

EE325: Probability & Random Processes, *Fall '20*PH107: Quantum Mechanics, *Fall '17*

**Mentor, Department Academic Mentorship Program, IIT Bombay**    *Apr '19 - May '21*

Recipient of the **Institute Journalism Special Mention Award** at IIT Bombay

*Apr '18 - Mar '19*

**Convenor, IIT Bombay Broadcasting Channel**

*Apr '17 - Mar '18*

Official Multimedia Journalism Body | 50K+ YouTube Subscribers | 25K+ Facebook Followers

## Languages

## Software

Cadence, ADS, Genus, Innovus, TCAD Sentaurus, Bluespec, Altera Quartus, Xilinx Vivado, Code Composer Studio, Modelsim, GNURadio, AutoCAD, SolidWorks, MATLAB, Scilab, Octave, Origin, SPICE

## Prof. Anantha Chandrakasan, EECS

Prof. Souvik Mahapatra, EE

IITB | [E-Mail](#) | [Webpage](#)

Prof. Animesh Kumar, EE

Prof. Gerrit Bauer, Applied Sciences

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